



CAM / EUFANET- Industry Workshop – Programme

Wednesday, 21st September 2016 – Room B

09:30-10:50 *Session 13: EUFANET/CAM-Workshop "Automotive Electronics Systems Reliability" (Part 1)*

Qualification testing, warranties and recalls – the US perspective

Michael Pecht, CALCE (US)

Automotive Memory and Reliability

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14:50-16:30 *Session 16B: EUFANET/CAM-Workshop "Automotive Electronics Systems Reliability" (Part 2)*

77Ghz Automotive RADAR in eWLB package: from consumer to automotive packaging

Gerhard Haubner and Walter Hartner, Infineon (GER)

Reliability of automotive LED systems

Wolfgang Pohlmann, Hella (GER)

Powertrain electronics reliability

Mihai Nica, AVL (GER)

Requirements for Reliability and new Solutions for Transmission Control Units

Michael Novak, Conti (GER)

Capability of Cu wire bonding for automotive electronics

Rene Rongen, NXP (NL)

16:50-18:30 *Session 18B: EUFANET/CAM-Workshop "Automotive Electronics Systems Reliability" (Part 3)*

Si IGBT reliability for HVs

Satoshi Yasuda, Toyota (JPN)

Power modules, qualification and test

Martin Rittner, Bosch (GER)

Reliability of inverters and DC Link capacitors for e-mobility

Tim Langer, VW (GER)

Reliability of electronics for starter electronics

Amelie Thionville, Valeo (F)

Batteries and their reliability with special respect to traction applications

Marcel Held, EMPA (CH)
